

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLN. OF: ANDRE ET AL.

FILED: June 27, 2003

FOR: THIN LAYER OF HAFNIUM OXIDE AND DEPOSIT PROCESS

DOCKET: BREV 13186 DIV

MAIL STOP PATENT APPLICATION

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

The present application is a divisional of U.S. Patent Application Serial No. 09/830,380, filed April 25, 2001. Applicant hereby attaches copies of Form PTO-1449 and Form PTO 892 from the parent application. Copies of the various prior art references listed in the attached Forms PTO-1449 and PTO-892 are not being furnished, since they are available in the parent application. Accordingly, it is respectfully submitted that no copies of these references are believed necessary. The claims in the present application are believed to be patentably distinguished over these references.

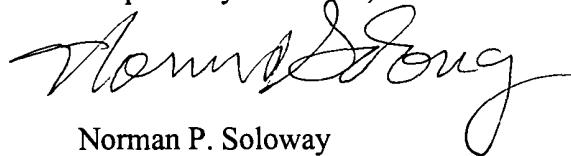
This information disclosure statement is being made pursuant to the duty of disclosure imposed by law and formulated in 37 CFR 1.56(A). No representation is made that the information thus disclosed in fact constitutes prior art or that it is the closest prior art, inasmuch as 37 CFR 1.56(A) relies on a materiality concept which depends on subjectivity.

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In the event there are any fee deficiencies or additional fees are payable, please charge them (or credit any overpayment) to our Deposit Account No. 08-1391.

Respectfully submitted,



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**CERTIFICATE OF EXPRESS MAILING**

“Express Mail” Mailing Label No: EU235897748US  
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I hereby certify that this paper and the papers listed thereon are being deposited with the United States Postal Service “Express Mail Post Office to Addressee” service under 37 CFR 1.10 on the date indicated above, and is addressed to: MAIL STOP PATENT APPLICATION, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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<b>Notice of References Cited</b>		Application/Control No. 09/830,380	Applicant(s)/Patent Under Reexamination ANDRE ET AL.	
		Examiner Tamra L. Dicus	Art Unit 1774	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
✓	A	US-5,399,435	03-1995	Ando et al.	428/428
✓	B	US-5,623,375	04-1997	Floch et al.	359/871
✓	C	US-5,691,044	11-1997	Oyama et al.	313/461
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>	Docket Number (Optional) <b>BREV 13186</b>	Application Number  
Applicant(s) <b>ANDRE et al</b>		
Filing Date <b>APRIL 25, 2001</b>	Group Art Unit  	

## U.S. PATENT DOCUMENTS

## FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
	0 486 475 A2	03-03-89	EUROPE	C 03 C	17/23		

**OTHER DOCUMENTS** *(Including Author, Title, Date, Pertinent Pages, Etc.)*

	<p>"Influence of Microstructure on Laser Damage Threshold of IBS Coatings" by C. J. Stolz et al          SPIE Vol. 2714 XP-002111763, pgs. 351-359</p>
	<p>"Thin Films for Optical Systems" edited by F.R. Flory          Ecole Nationale Superieure de Physique de Marseille, Marseille, France          Pgs. 521-549</p>

**EXAMINER** \_\_\_\_\_ **DATE CONSIDERED** \_\_\_\_\_

**EXAMINER:** Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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(Use several sheets if necessary)

Docket Number (Optional)	BREV 13186	Application Number
Applicant(s)	ANDRE et al	
Filing Date	APRIL 25, 2001	Group Art Unit

*EXAMINER INITIAL	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)
	"Optical Coatings Deposited by Reactive Ion Plating" by A.J. Waldorf et al Applied Optics/October 1, 1993/Vol. 32, No. 28 pgs. 5583-5593
	"Optical Coatings for High-Power Neodymium Lasers" by B. Brauns et al Sov. J. Quantum Electron 18 (10) Oct. 1988, c 1989 American Institute of Physics pgs. 1286-1290
	"Investigation of Optical Damage Mechanisms in Hafnia and Silica Thin Films Using Pairs of Subnanosecond Laser Pulses with Variable Time Delay" by L.L. Chase, et al J. Appl. Phys. 71 (3) February 1, 1992/American Institute of Physics pgs. 1204-1208
	"Characterization of Defect Geometries in Multilayer Optical Coatings" by R.J. Tench et al J. Vac. Sci. Technol. A 12(5), Sep/Oct 1994 1994 American Vacuum Society pgs. 2808-2813
	"Reactive Evaporation of Low-Defect Density Hafnia" by R.Chow et al Applied Optics/ October 1, 1993/ Vol. 32, No. 28/ pgs. 5567-5574
	"Stress and Environmental Shift Characteristics of HfO <sub>2</sub> /Si)2 Multilayer Coatings" by J.F. Anzellotti et al Proceedings Reprint/SPIE - The International Society for Optical Engineering Reprinted from 28th Annual Boulder Damage Symposiumproceedings "Laser-Induced Damage in Optical Materials: 1996" October 7-9, 1996, Boulder, Colorado SPIE Vol. 2966, pgs. 258-264
	"Study of the Structure and Properties of Thick Vacuum Condensates of Nickel, Titanium, Tungsten, Aluminum Oxide and Zirconium Dioxide" by B.A. Movchan et al F metal.metalloved., 28, No. 4, 653-660, 1969 pgs. 83-90
	"Nano Absorbing Centers: A Key Point in Laser Damage of Thin Films" by J. Dijon et al SPIE Vol. 2966, pgs 315-325
EXAMINER	DATE CONSIDERED

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